

Silicon Carbide (SiC) MOSFET - EliteSiC, 12 mohm, 650 V, M3S, TO247-4L, Thin Leads

NTH4LN012N065M3S

Features

- Typical $R_{DS(ON)} = 12 \text{ m}\Omega @ V_{GS} = 18 \text{ V}$
- Ultra Low Gate Charge ($Q_{G(tot)} = 135 \text{ nC}$)
- High Speed Switching with Low Capacitance ($C_{OSS} = 281 \text{ pF}$)
- 100% Avalanche Tested
- This Device is Halide Free and RoHS Compliant with Exemption 7a, Pb-Free 2LI (on second level interconnection)

Applications

- SMPS, Solar Inverters, UPS, Energy Storage, EV Charging Infrastructure

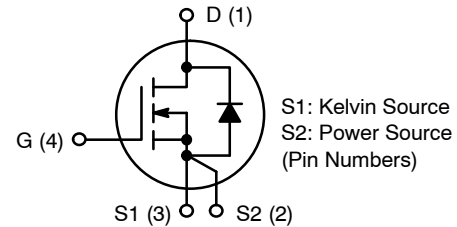
MAXIMUM RATINGS ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V_{DSS}	650	V
Dynamic Gate-to-Source Voltage	V_{GS}	-10/ 22.6	V
Gate-to-Source Transient Voltage	$t_p < 0.5 \mu\text{s}$, Duty cycle $\leq 1\%$	V_{GS}	-11 / +25
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	102
Power Dissipation		P_D	375
Continuous Drain Current	$T_C = 100^\circ\text{C}$	I_D	81
Power Dissipation		P_D	187
Pulsed Drain Current (Note 1)	$T_C = 25^\circ\text{C}$ $t_p = 100 \mu\text{s}$	I_{DM}	330
Continuous Source-Drain Current (Body Diode)	$T_C = 25^\circ\text{C}$ $V_{GS} = -3 \text{ V}$	I_S	62
	$T_C = 100^\circ\text{C}$ $V_{GS} = -3 \text{ V}$		35
Pulsed Source-Drain Current (Body Diode) (Note 1)	$T_C = 25^\circ\text{C}$ $V_{GS} = -3 \text{ V}$ $t_p = 100 \mu\text{s}$	I_{SM}	250
Single Pulse Avalanche Energy ($I_{LPK} = 72 \text{ A}$, $L = 0.1 \text{ mH}$) (Note 2)	E_{AS}	259	mJ
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to +175	$^\circ\text{C}$
Lead Temperature for Soldering Purposes (1/8" from case for 10 seconds)	T_L	270	$^\circ\text{C}$

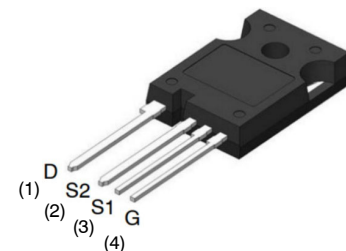
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Single pulse, limited by max junction temperature.
2. EAS of 259 mJ is based on starting $T_J = 25^\circ\text{C}$, $L = 0.1 \text{ mH}$, $I_{AS} = 72 \text{ A}$, $V_{DD} = 100 \text{ V}$, $V_{GS} = 18 \text{ V}$.

$V_{(BR)DSS}$	$R_{DS(ON)} \text{ TYP}$	$I_D \text{ MAX}$
650 V	12 m $\Omega @ 18 \text{ V}$	102 A

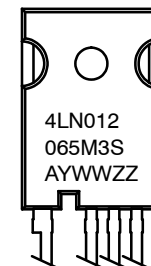


N-CHANNEL MOSFET



TO-247-4L, Thin Leads
CASE 340CW

MARKING DIAGRAM



4LN012065M3S = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping
NTH4LN012N065M3S	TO-247-4L, Thin Leads	30 Units / Tube

NTH4LN012N065M3S

THERMAL CHARACTERISTICS

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Note 3)	$R_{\theta JC}$	0.40	$^{\circ}\text{C}/\text{W}$

3. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Value	Unit
Operation Values of Gate-to-Source Voltage	V_{GSop}	-5 ... 0 +18	V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
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OFF CHARACTERISTICS

Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}, I_D = 1\text{ mA}, T_J = 25^{\circ}\text{C}$	650			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 650\text{ V}, T_J = 25^{\circ}\text{C}$			10	μA
		$V_{DS} = 650\text{ V}, T_J = 175^{\circ}\text{C}$ (Note 5)			500	μA
Gate-to-Source Leakage Current	I_{GSS}	$V_{GS} = -10\text{ V}, V_{DS} = 0\text{ V}$	-1			μA
		$V_{GS} = +22.6\text{ V}, V_{DS} = 0\text{ V}$			1	

ON CHARACTERISTICS

Drain-to-Source On Resistance	$R_{DS(on)}$	$V_{GS} = 18\text{ V}, I_D = 40\text{ A}, T_J = 25^{\circ}\text{C}$		12	17	$\text{m}\Omega$
		$V_{GS} = 18\text{ V}, I_D = 40\text{ A}, T_J = 175^{\circ}\text{C}$ (Note 5)		18		
		$V_{GS} = 15\text{ V}, I_D = 40\text{ A}, T_J = 25^{\circ}\text{C}$		15		
		$V_{GS} = 15\text{ V}, I_D = 40\text{ A}, T_J = 175^{\circ}\text{C}$ (Note 5)		20		
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 20\text{ mA}, T_J = 25^{\circ}\text{C}$	2.0	2.7	4.0	V
Forward Transconductance	g_{FS}	$V_{DS} = 10\text{ V}, I_D = 40\text{ A}$ (Note 5)		45		S

CHARGES, CAPACITANCES & GATE RESISTANCE

Input Capacitance	C_{ISS}	$V_{DS} = 400\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$ (Note 5)		3610		pF
Output Capacitance	C_{OSS}			281		
Reverse Transfer Capacitance	C_{RSS}			24		
Total Gate Charge	$Q_{G(TOT)}$	$V_{DD} = 400\text{ V}, I_D = 40\text{ A}, V_{GS} = -3/18\text{ V}$ (Note 5)		135		nC
Gate-to-Source Charge	Q_{GS}			35		
Gate-to-Drain Charge	Q_{GD}			29		
Gate Resistance	R_G	$f = 1\text{ MHz}$		1.6		Ω

SWITCHING CHARACTERISTICS

Turn-On Delay Time	$t_{d(ON)}$	$V_{GS} = -3/18\text{ V}, I_D = 40\text{ A}, V_{DD} = 400\text{ V}, R_G = 4.7\text{ }\Omega, T_J = 25^{\circ}\text{C}$ (Notes 4, 5)		5		ns
Turn-Off Delay Time	$t_{d(OFF)}$			49		
Rise Time	t_r			23		
Fall Time	t_f			12		
Turn-On Switching Loss	E_{ON}			143		μJ
Turn-Off Switching Loss	E_{OFF}			145		
Total Switching Loss	E_{TOT}			288		

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ELECTRICAL CHARACTERISTICS ($T_J = 25\text{ }^{\circ}\text{C}$ unless otherwise specified) (continued)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	$t_{d(ON)}$	$V_{GS} = -3/18\text{ V}$, $I_D = 40\text{ A}$, $V_{DD} = 400\text{ V}$, $R_G = 4.7\text{ }\Omega$, $T_J = 175\text{ }^{\circ}\text{C}$ (Notes 4, 5)		3.6		ns
Turn-Off Delay Time	$t_{d(OFF)}$			60		
Rise Time	t_r			23		
Fall Time	t_f			13		
Turn-On Switching Loss	E_{ON}			142		μJ
Turn-Off Switching Loss	E_{OFF}			172		
Total Switching Loss	E_{TOT}			314		

SOURCE-TO-DRAIN DIODE CHARACTERISTICS

Forward Diode Voltage	V_{SD}	$I_{SD} = 40\text{ A}$, $V_{GS} = -3\text{ V}$, $T_J = 25\text{ }^{\circ}\text{C}$		4.5	6.0	V
		$I_{SD} = 40\text{ A}$, $V_{GS} = -3\text{ V}$, $T_J = 175\text{ }^{\circ}\text{C}$ (Note 5)		4.2		
Reverse Recovery Time	t_{RR}	$V_{GS} = -3\text{ V}$, $I_S = 40\text{ A}$, $di/dt = 1000\text{ A}/\mu\text{s}$, $V_{DS} = 400\text{ V}$, $T_J = 25\text{ }^{\circ}\text{C}$ (Note 5)		26		ns
Charge Time	t_a			15		
Discharge Time	t_b			11		
Reverse Recovery Charge	Q_{RR}			195		nC
Reverse Recovery Energy	E_{REC}			16		μJ
Peak Reverse Recovery Current	I_{RRM}			13		A

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. E_{ON}/E_{OFF} result is with body diode.

5. Defined by design, not subject to production test.

TYPICAL CHARACTERISTICS

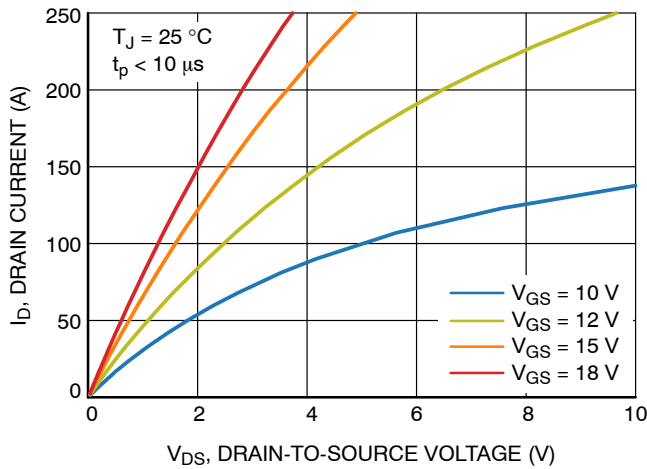


Figure 1. Output Characteristics

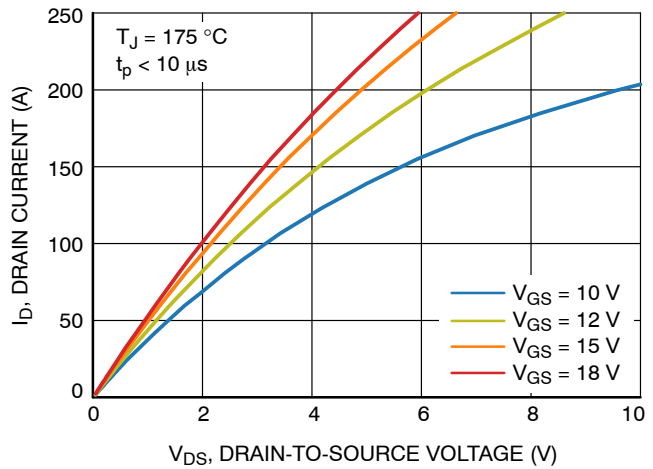


Figure 2. Output Characteristics

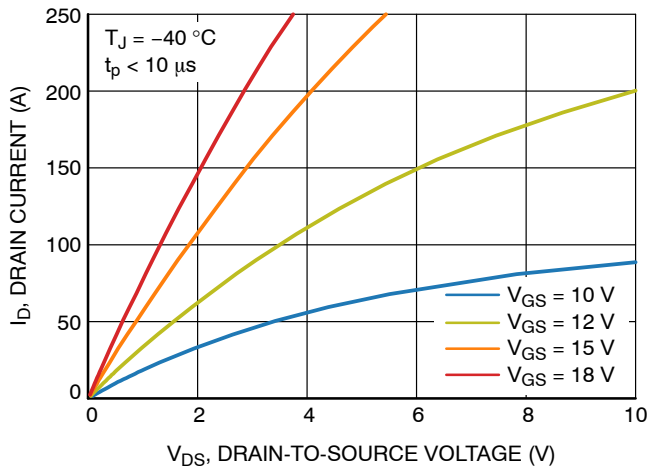


Figure 3. Output Characteristics

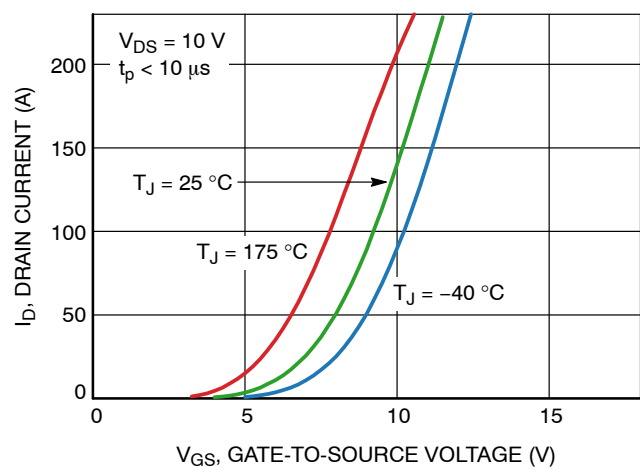


Figure 4. I_D vs. V_{GS}

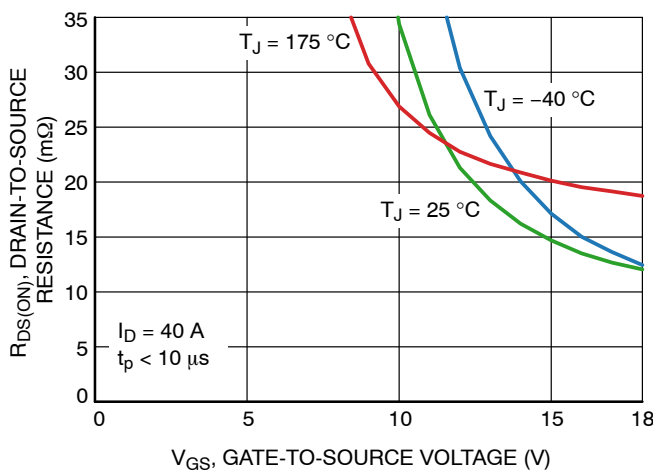


Figure 5. $R_{DS(ON)}$ vs. V_{GS}

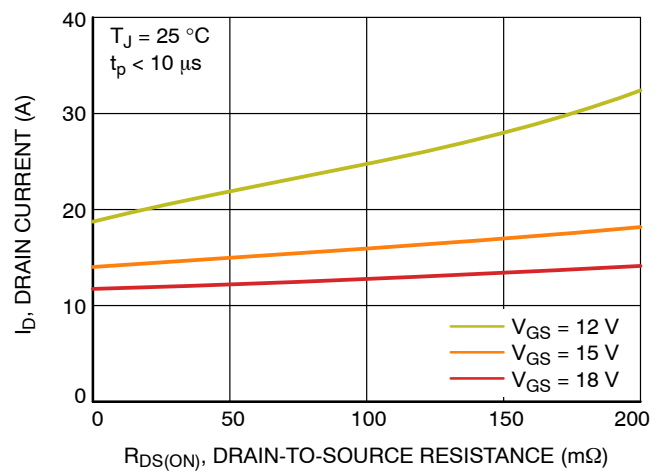


Figure 6. I_D vs. $R_{DS(ON)}$

TYPICAL CHARACTERISTICS

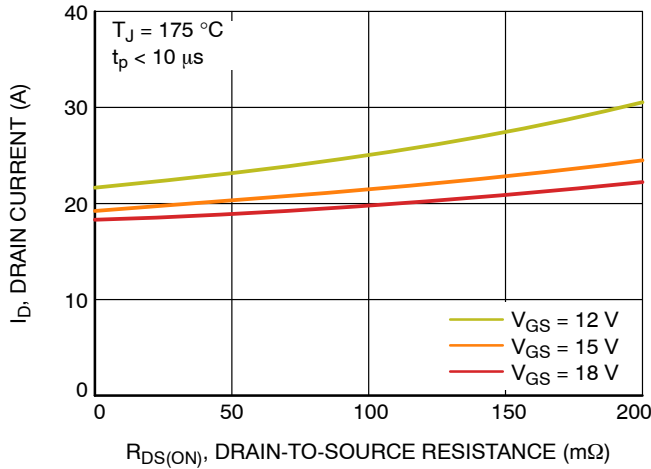


Figure 7. I_D vs. $R_{DS(ON)}$

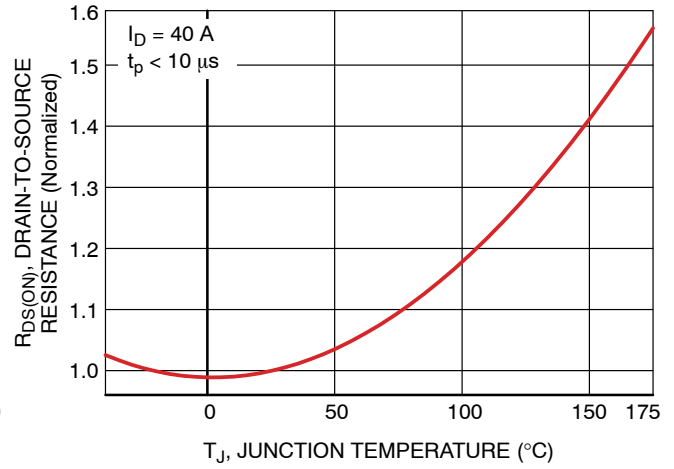


Figure 8. $R_{DS(ON)}$ vs. T_J

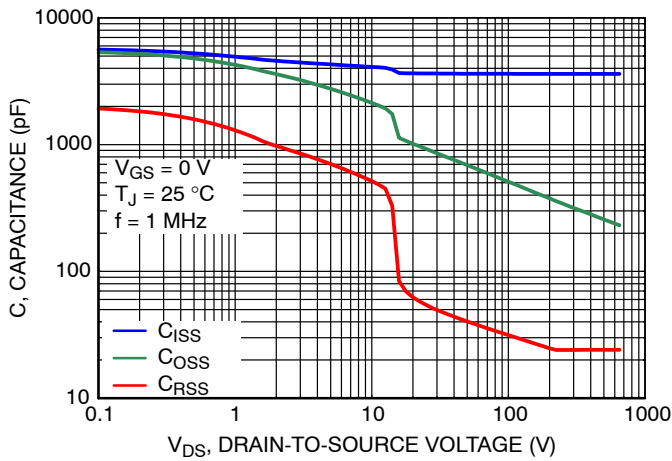


Figure 9. Capacitance Characteristics

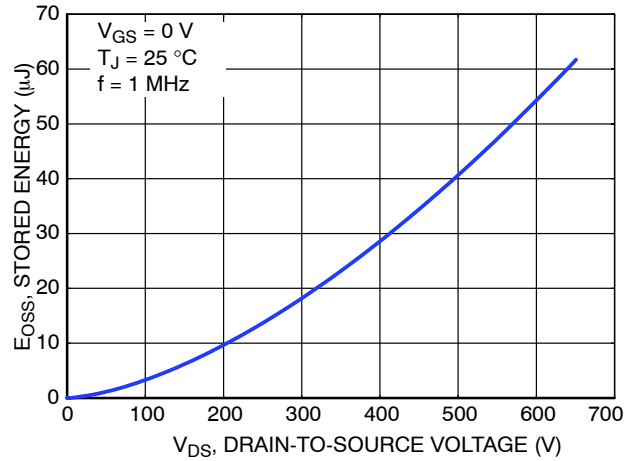


Figure 10. Stored Energy vs. Drain to Source Voltage

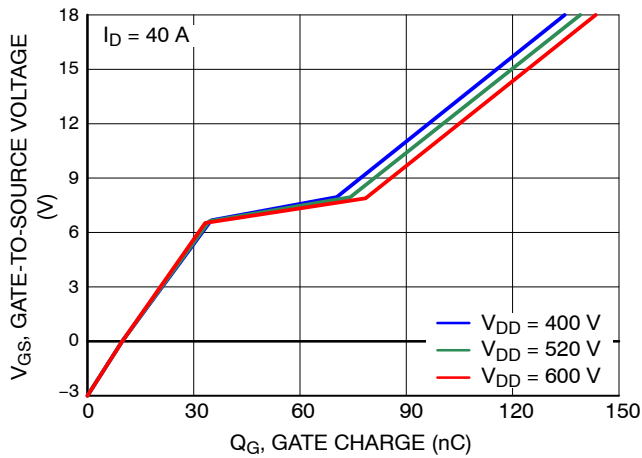


Figure 11. Gate Charge Characteristics

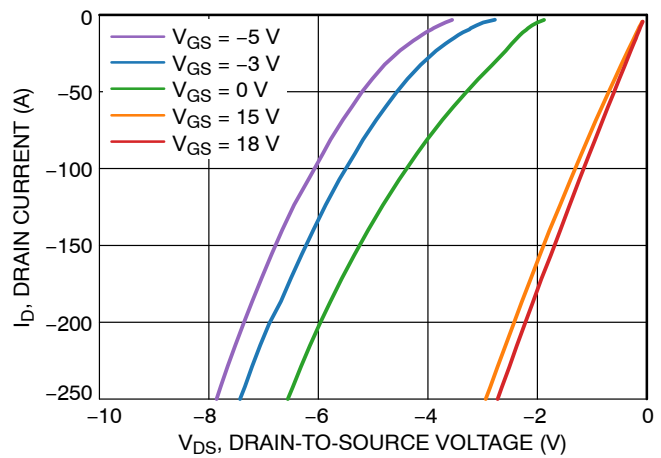


Figure 12. Reverse Conduction Characteristics

TYPICAL CHARACTERISTICS

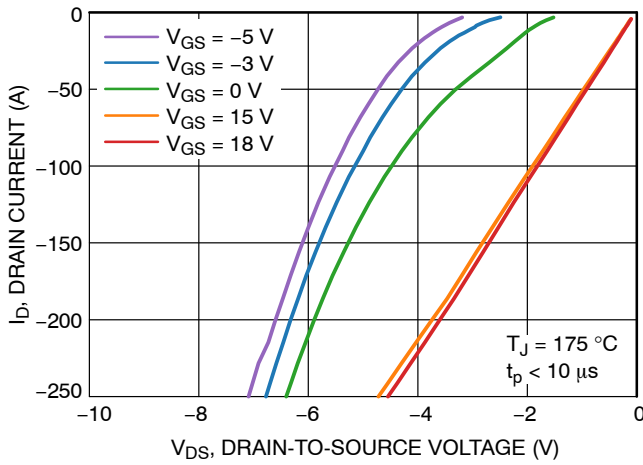


Figure 13. Reverse Conduction Characteristics

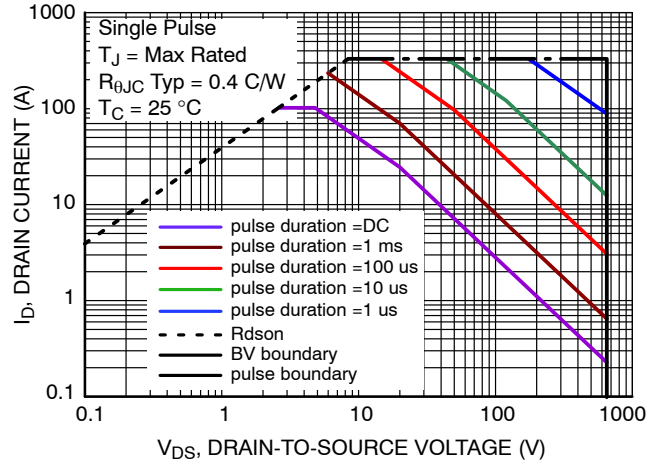


Figure 14. Safe Operating Area

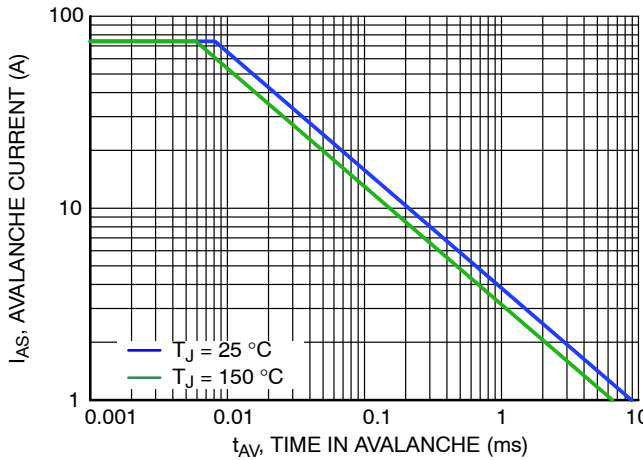


Figure 15. Avalanche Current vs. Pulse Time (UIS)

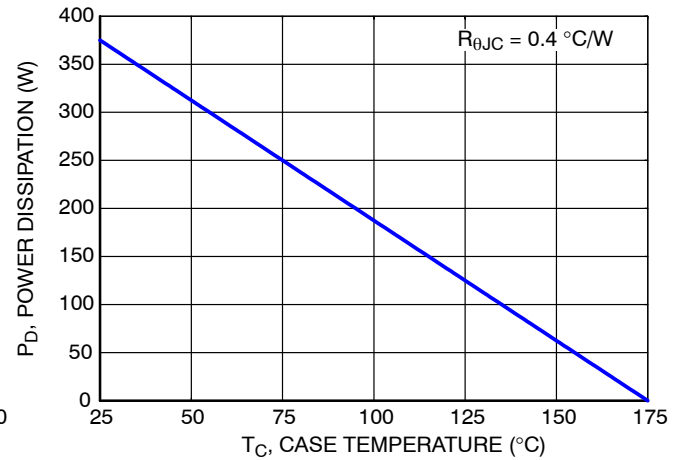


Figure 16. Maximum Power Dissipation vs. Case Temperature

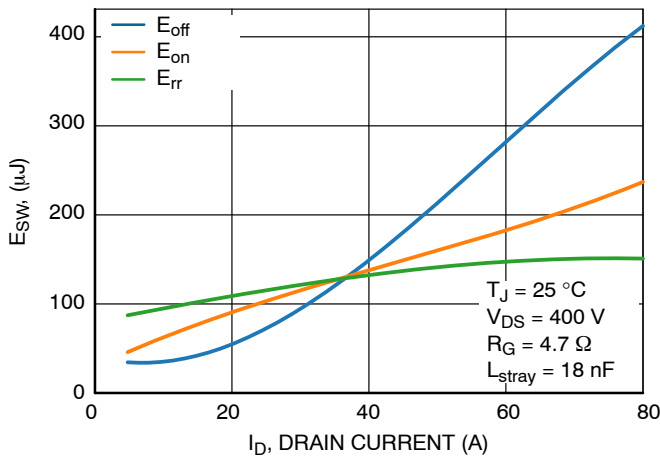


Figure 17. Inductive Switching Loss vs. Drain Current

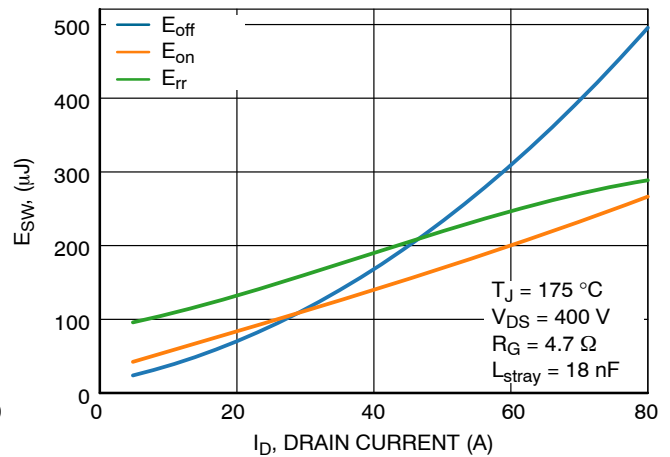


Figure 18. Inductive Switching Loss vs. Drain Current

TYPICAL CHARACTERISTICS

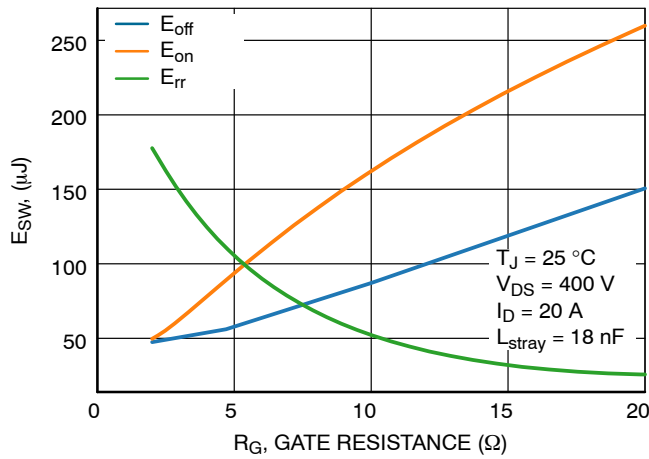


Figure 19. Inductive Switching Loss vs. Gate Resistance

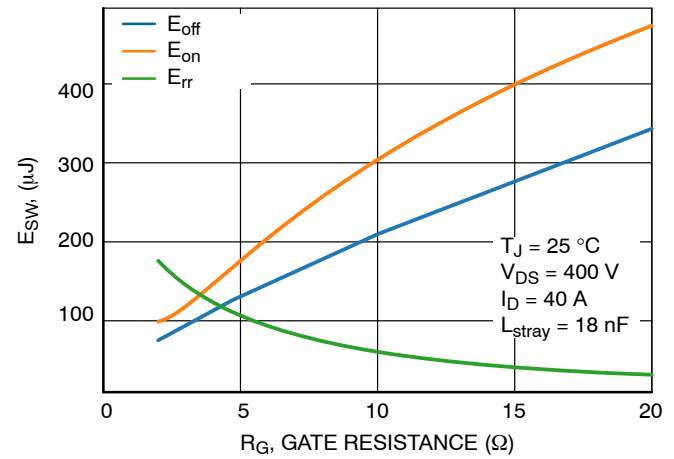


Figure 20. Inductive Switching Loss vs. Gate Resistance

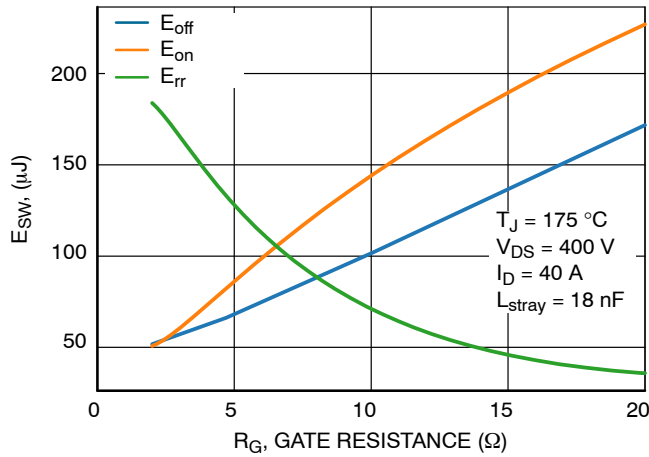


Figure 21. Inductive Switching Loss vs. Gate Resistance

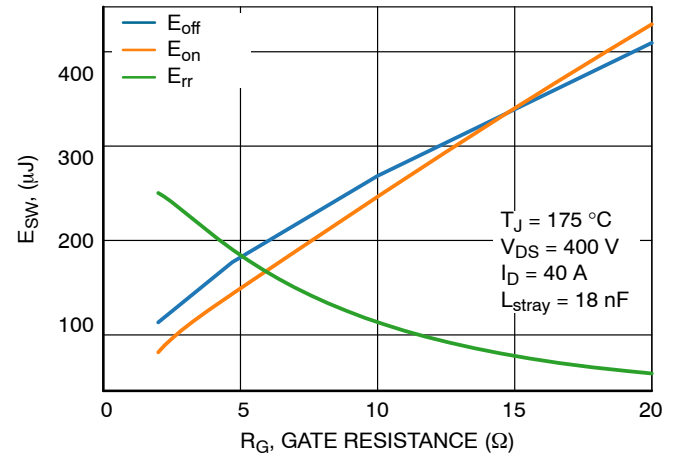


Figure 22. Inductive Switching Loss vs. Gate Resistance

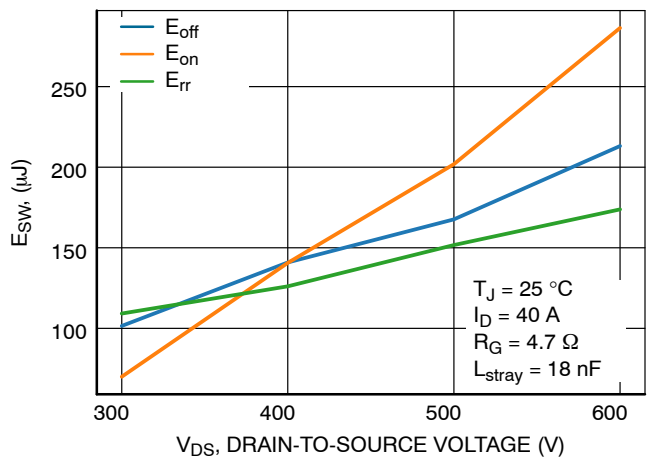


Figure 23. Inductive Switching Loss vs. Drain Voltage

TYPICAL CHARACTERISTICS

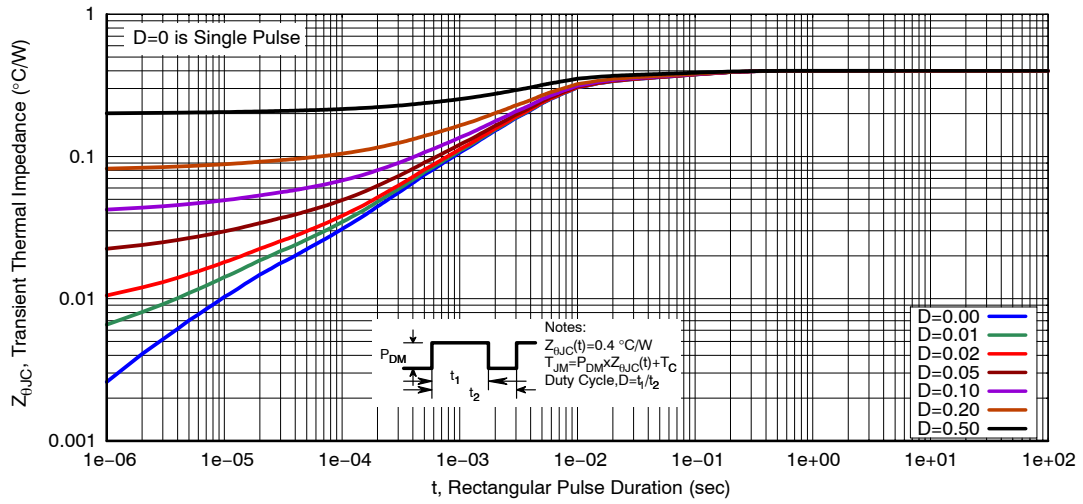
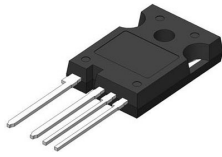


Figure 24. Thermal Response Characteristics

NTH4LN012N065M3S

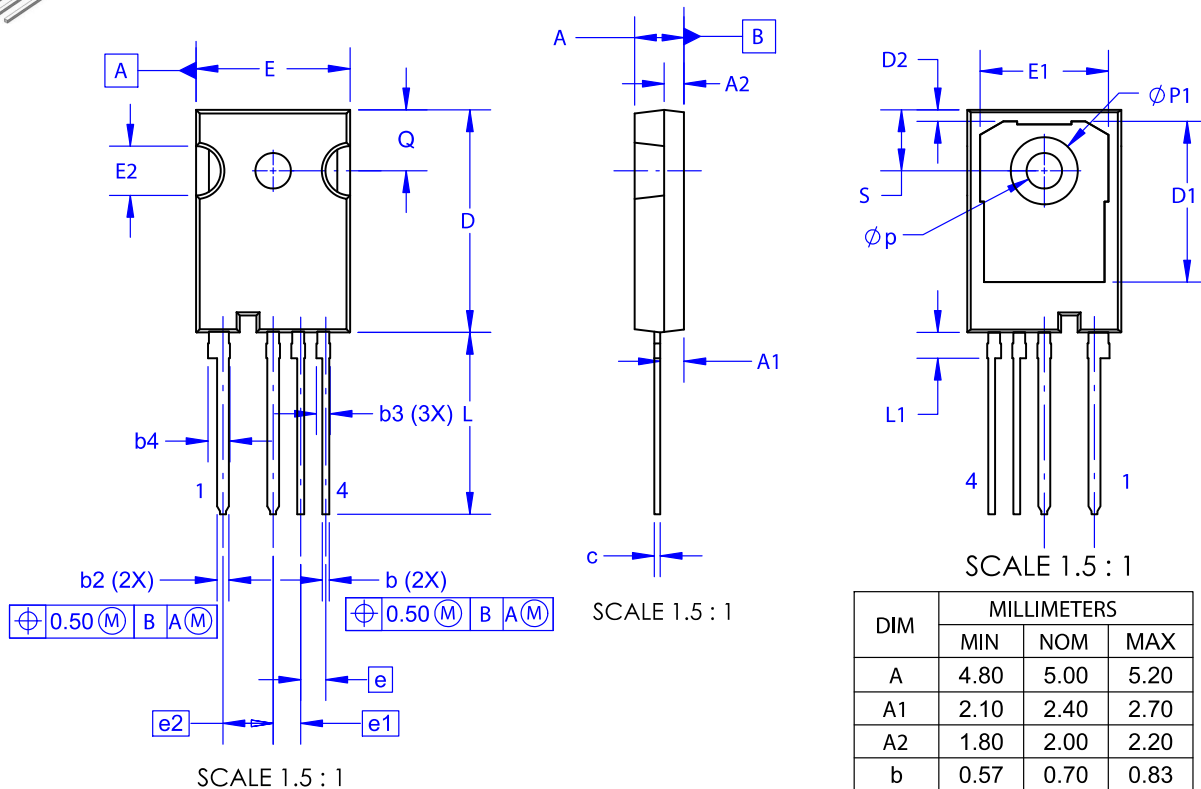
REVISION HISTORY

Revision	Description of Changes	Date
0	Initial document release.	7/23/2026
1	Added Gate-to-Source Transient Voltage specification.	8/3/2026



TO-247 4-LEAD, THIN LEADS
CASE 340CW
ISSUE A

DATE 16 SEP 2019



NOTES:

- A. NO INDUSTRY STANDARD APPLIES TO THIS PACKAGE.
- B. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR EXTRUSIONS.
- C. ALL DIMENSIONS ARE IN MILLIMETERS.

DIM	MILLIMETERS		
	MIN	NOM	MAX
A	4.80	5.00	5.20
A1	2.10	2.40	2.70
A2	1.80	2.00	2.20
b	0.57	0.70	0.83
b2	1.07	1.20	1.33
b3	1.20	1.40	1.60
b4	2.02	2.22	2.42
c	0.50	0.60	0.70
D	22.34	22.54	22.74
D1	16.00	16.30	16.50
D2	0.97	1.17	1.37
e		2.54	
e1		2.79	
e2		5.08	
E	15.40	15.60	15.80
E1	12.80	13.00	13.20
E2	4.80	5.00	5.20
L	18.12	18.42	18.72
L1	2.42	2.62	2.82
Øp	3.40	3.60	3.80
ØP1	6.60	6.80	7.00
Q	5.97	6.17	6.37
S	5.97	6.17	6.37

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